

Search Notes 				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/787,015	CHIN ET AL.	
				Examiner	Art Unit	
				David M. Naff	1851	
SEARCHED				SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
Class	Subclass	Date	Examiner		DATE	EXMR
				<i>West</i>	<i>10/2/06</i>	<i>an</i>
				<i>Geo printart</i>		
				<i>to date</i>	<i>4/14/07</i>	<i>an</i>
				<i>to date</i>	<i>6/24/07</i>	<i>an</i>
				<i>to date</i>	<i>7/18/07</i>	<i>an</i>
				<i>West + STX</i>		
				<i>Geo printart</i>		
INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
PG. Pub		<i>7/28/07</i>	<i>an</i>			
				<i>Geo printart</i>		